

**INFORMATION  
DISCLOSURE  
STATEMENT**

OMB No. 0651-0011

Atty. Docket No.:

Serial No.:

53321USA9B

09/358,738

Applicant(s):

Craig S. Chamberlain, et al.

Filing Date:

7/21/99

Group:

1743

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	SubClass	Filing Date If Appropriate
/	4,131,064	12/26/78	Ryan et al.			
	4,618,525	10/21/86	Chamberlain et al.			
	4,944,185	7/31/90	Clark, Jr. et al.			
	5,409,968	4/25/95	Clatanoff et al.			
	5,453,291	9/26/95	Sasahara et al.			
	5,504,281	4/2/96	Whitney et al.			
	5,640,088	6/17/97	Sasahara et al.			

**FOREIGN PATENT DOCUMENTS**

Document Number	Date of Publication	Country	Class	SubClass	Translation
2 219 405	12/6/89	GB	1	2	Yes No

**OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)**

1	Abstract of SU 1597614, XP-002070371
2	F.P. Sun, et al. "Magnetic Activation of Embedded Sensory Particles in Active Tagging Interrogation of Adhesive Bonding, 1993, pp. 400-409
3	Abstract of W.G. Clark, Jr., "Magnetic Particle Tagging for Process Control in Composite Fabrication", 1995.
4	W.G. Clark Jr., "Magnetic Tagging Monitors Bond Integrity and Thickness", June, 1992, pp. 22-26.
	Giurgiutiu, et al., J. Intell. Mater. Syst. Struct. (1996) 7(6) "Passive and Active Tagging of Glass-Fiber Polymeric Composites for In-Process and In-Field Non-Destructive Evaluation", November, 1996, pp. 623-634

**EXAMINER**JAN LUDLOW  
PRIMARY EXAMINER

Date Considered

9/01

\*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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					Yes No

**OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)**

5	/		Troy W. Barbee, Jr., et al., "Microstructure of Amorphous 304 Stainless Steel-Carbon Alloys Synthesized by Magnetron Sputter Deposition", paper presented at the International Conference on Metallurgical Coatings, San Diego, CA, April 23-27, 1979, pp. 143-150
6	/		Victor Giurgiutiu, et al., "Passive and Active Tagging of Reinforced Composites for In Process and In-Field Non-Destructive Evaluation", SPIE Vol. 2717, pp. 361-372
7	/		Suwei Zhou, et al., "Review of Embedded Particle Tagging Methods for NDE of Composite Materials and Structures", SPIE Vol. 2444, pp. 39-52
8	/		S. Zhou, et al., "An In-Situ Sensory Technique for In-Service Quality Monitoring - Measurement of the Complex Young's Modulus of Polymers", SPIE Vol. 1918, pp. 14-23, 1993
9	/		William G. Clark Jr., et al., "Tagging Lets You Test the Untestable", pp. 59-69
10	/		A. Lekatou, et al., "Elasticity and Fracture in Particulate Composites with Strong and Degraded Interfaces", J. Mater. Res., Vol 11, No. 5, pp. 1293-1304
4	/		A. Lekatou, et al., "Elasticity and Fracture in Particulate Composites with Strong and Degraded Interfaces", Journal of Materials Research, Vol 11, No. 5, pp. 1293-1304, May 1996
12	/		Walther, Ph.D., "Electrical Stability During Vibration and Electromagnetic Pulse Survivability of Silver-Plated Glass Bead Filled EMI Shielding Gaskets", ©1989, pp. 40-45
13	/		Suwei Zoug, et al., "An Active Particle Tagging Method using Magnetic Excitation for Material Diagnostics", A Collection of Technical Papers, Part 5, April 10-13, 1995/New Orleans, LA, pp. 3260-3268

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